Power MOSFET 25 V, 129 A, Single N-Channel, ICEPAK

Features

- Low Package Inductance
- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- Dual Sided Cooling Capability
- Compatible with MX Footprint and Outline
- This is a Pb-Free Device

Applications

- CPU Power Delivery
- DC-DC Converters
- Optimized for Synch FET

MAXIMUM RATINGS ($T_J = 25^{\circ}C$ unless otherwise stated)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			V_{DSS}	25	V
Gate-to-Source Voltage	Gate-to-Source Voltage			±20	V
Continuous Drain		T _A = 25°C	Ι _D	26.7	Α
Current R _{θJA} (Note 1)		T _A = 70°C		21.4	
Power Dissipation $R_{\theta JA}$ (Note 1)		T _A = 25°C	P _D	2.8	W
Continuous Drain		T _A = 25°C	I _D	129	Α
Current R _{0J-PCB} (Note 2)	Steady State	T _A = 70°C		72	
Power Dissipation $R_{\theta J-PCB}$ (Note 2)	State	T _A = 25°C	P _D	65	W
Continuous Drain		T _C = 25°C	I _D	151	Α
Current R _{θJC} (Note 1)		T _C = 70°C		121	
Power Dissipation R _{0JC} (Note 1)		T _C = 25°C	P _D	89	W
Pulsed Drain Current	T _A = 25°0	C, t _p = 10 μs	I _{DM}	210	Α
Current Limited by Packa	ge	T _A = 25°C	I _{Dmax}	50	Α
Operating Junction and Storage Temperature			T _J , T _{stg}	–55 to 150	ô
Source Current (Body Diode) (Note 1)			IS	112	Α
Drain to Source DV/DT			dV/dt	6.0	V/ns
Single Pulse Drain–to–Source Avalanche Energy ($T_J=25^{\circ}C$, $V_{DD}=25$ V, $V_{GS}=10$ V, $I_L=35$ A_{pk} , $L=0.3$ mH, $R_{G}=25$ Ω)			E _{AS}	184	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	270	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

- 1. Surfacemounted on FR4 board using 1 sq-in pad, 1 oz Cu.
- 2. Measured with a T_J of approximately 90°C using 1 oz Cu board.
- 3. Surfacemounted on FR4 board using 1 sq-in pad, 2 oz Cu.



ON Semiconductor®

http://onsemi.com

V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX	
25 V	2.6 mΩ @ 10 V	129 A	
25 V	3.8 mΩ @ 4.5 V	123 A	



ICEPAK E1 PAD CASE 145AE

MARKING DIAGRAM

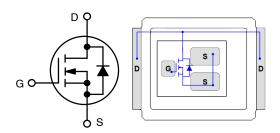


E4891 = Specific Device Code A = Assembly Location

A = Assembly Location
Y = Year

WW = Work Week
■ = Pb-Free Package

(Note: Microdot may be in either location)



N-CHANNEL MOSFET

ORDERING INFORMATION

Device	Package	Shipping [†]
NTMKE4891NT1G	ICEPAK (Pb-Free)	1500/Tape & Reel
NTMKE4891NT3G	ICEPAK (Pb-Free)	5000/Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

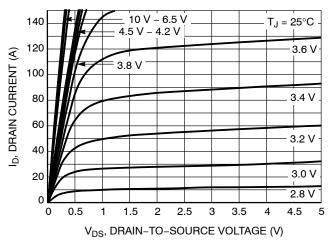
THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain) (Note 1)	$R_{ heta JC}$	1.4	°C/W
Junction-to-Ambient - Steady State (Note 1)	$R_{ heta JA}$	45	
Junction-to-Ambient - Steady State (Notes 2 and 3)	$R_{\theta JA}$	20	
Junction-to-PCB (Note 2)	$R_{\theta J-PCB}$	1.0	

Parameter	Symbol	Test Condition	on	Min	Тур	Max	Unit
OFF CHARACTERISTICS	•		•		•	•	•
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	V _{GS} = 0 V, I _D = 2	50 μΑ	25			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /T _J				21		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	.,,	T _J = 25°C			1.0	μΑ
		$V_{GS} = 0 \text{ V}, V_{DS} = 20 \text{ V}$	T _J = 125°C			10	
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V _{GS} =	±20 V			±100	nA
ON CHARACTERISTICS (Note 4)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D = 2$	250 μΑ	1.4		2.4	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				6.0		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V, I _D =	29 A		2.1	2.6	mΩ
		V _{GS} = 4.5 V, I _D =	23 A		3.1	3.8	
Forward Transconductance	9FS	V _{DS} = 1.5 V, I _D =	: 23 A		28		S
CHARGES, CAPACITANCES AND GA	ATE RESISTAN	ICE					
Input Capacitance	C _{iss}				4360		pF
Output Capacitance	C _{oss}	V _{GS} = 0 V, f = 1.0 MHz	V _{DS} = 15 V		970		7
Reverse Transfer Capacitance	C _{rss}		ŀ		540		
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 4.5 V, V _{DS} = 15 V, I _D = 23 A			33		nC
Threshold Gate Charge	Q _{G(TH)}				4.5		7
Gate-to-Source Charge	Q_{GS}				11.6		
Gate-to-Drain Charge	Q_{GD}		•		12.4		
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 10 V, V _{DS} = 15 V, I _D = 23 A			66		nC
SWITCHING CHARACTERISTICS (No	ote 5)				•		•
Turn-On Delay Time	t _{d(on)}				19.1		ns
Rise Time	t _r	V _{GS} = 4.5 V, V _{DS} :	= 15 V.		13.6		1
Turn-Off Delay Time	t _{d(off)}	$I_D = 23 \text{ A}, R_G =$	1.8 Ω ΄		30		
Fall Time	t _f				7.4		7
DRAIN-SOURCE DIODE CHARACTE	RISTICS				•		
Forward Diode Voltage	V _{SD}	V _{GS} = 0 V, I _S = 23 A	T _J = 25°C		0.8	1.0	V
		, GO , G	T _J = 125°C		0.65		
Reverse Recovery Time	t _{RR}	$V_{GS} = 0 \text{ V, } d_{IS}/d_t = 200 \text{ A/}\mu\text{s,}$ $I_S = 23 \text{ A}$			35		ns
Charge Time	t _a				16		
Discharge Time	t _b				19		
Reverse Recovery Charge	Q_{RR}				33		nC
PACKAGE PARASITIC VALUES							
Gate Resistance	R_{G}	T _A = 25°C			0.5	1.5	Ω

^{4.} Pulse Test: pulse width = 300 μs, duty cycle ≤ 2%.
5. Switching characteristics are independent of operating junction temperatures.

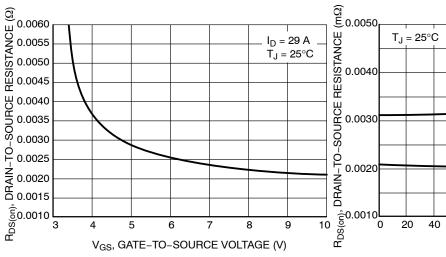
TYPICAL CHARACTERISTICS



200 $V_{DS} \ge 10 \text{ V}$ 180 160 ID, DRAIN CURRENT (A) 140 120 100 80 $T_J = 125^{\circ}C$ 60 40 20 $T_J = -55^{\circ}C$ 1.5 3.5 2.5 4.5 5 VGS, GATE-TO-SOURCE VOLTAGE (V)

Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics



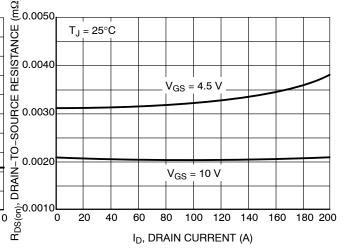


Figure 3. On-Resistance vs. Gate-to-Source Voltage

Figure 4. On-Resistance vs. Drain Current and Gate Voltage

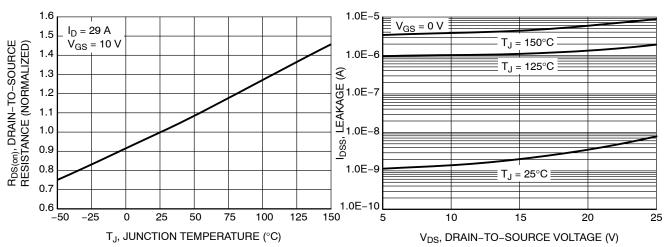


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL CHARACTERISTICS

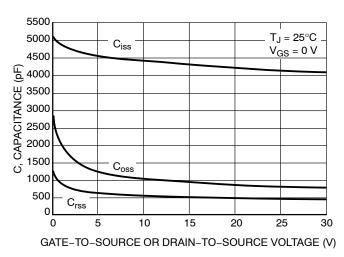


Figure 7. Capacitance Variation

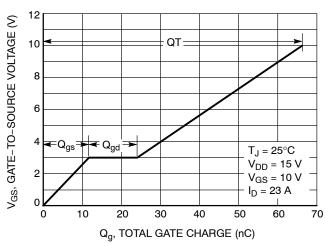


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

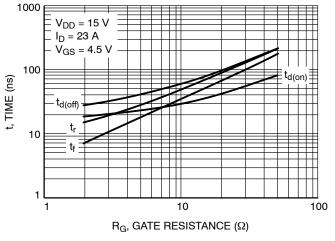


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

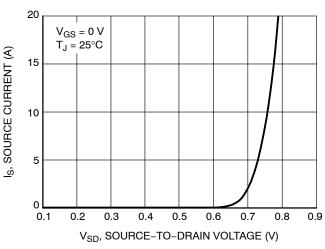


Figure 10. Diode Forward Voltage vs. Current

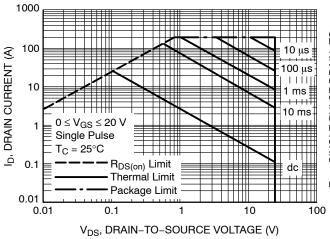


Figure 11. Maximum Rated Forward Biased Safe Operating Area

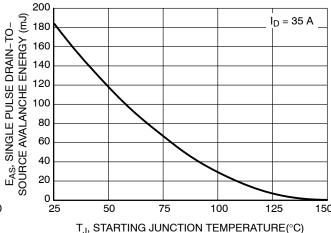
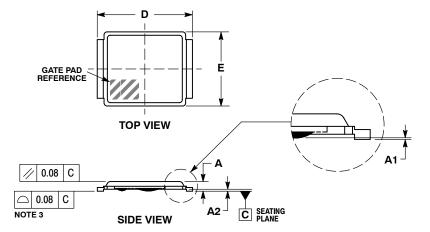


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

PACKAGE DIMENSIONS

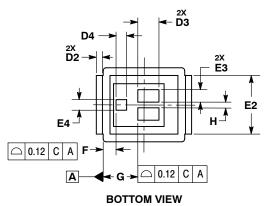
ICEPAK 6.3x4.9 - E1 PAD CASE 145AE-01 **ISSUE O**



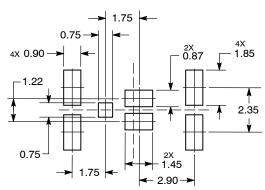
NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994. CONTROLLING DIMENSION: MILLIMETERS. COPLANARITY APPLIES TO THE FLANGES
- OF LEADFRAME ONLY.

OF ELFABITIVAME ONE!.				
	MILLIMETERS			
DIM	MIN	MAX		
Α	0.61	0.68		
A1	0.02	0.08		
A2	0.08	0.17		
D	6.25	6.35		
D2	0.35	0.45		
D3	1.34	1.38		
D4	0.64	0.68		
Е	4.80	5.05		
E2	3.85	3.95		
E3	0.76	0.80		
E4	0.64 0.68			
F	0.98 BSC			
G	2.38 BSC			
Н	0.38	0.42		



SOLDERING FOOTPRINT*



DIMENSIONS: MILLIMETERS

*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

The product described herein, NTMKE4891N, may be covered by U.S. Patents including 6,081,031. Other patents may be pending.

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